



**Test Report**

NO: GSI10050460804

Date: May 10, 2010

Page 1 of 6

**Customer:** HongKong Tenow International Ltd.

**Address:** Unit C-8A, Shennan Garden Building, High-Tech Park, Nanshan District, Shenzhen, China

**Report on the submitted sample said to be**

**Sample name:** Prof Revolution S2 8000 PCI-E

**Model:** Prof8000

**Item/Lot NO: /**

**Material: /**

**Buyer: /**

**Supplier: /**

**Manufacturer: /**

**Reports received date:** May 04-10, 2010

**Requisition:** To combine the test reports for the submitted sample

**Conclusion:** All reports as specified client, determine the Lead, Cadmium, Mercury, Hexavalent Chromium and/or PBB&PBDE content in the submitted sample which are restricted in Directive 2002/95/EC (ROHS).

\*\*\*\*\* FOR FURTHER DETAILS, PLEASE REFER TO THE FOLLOWING PAGE(S) \*\*\*\*\*

Signed for GSI Ltd.

Written by : Vincent

Inspected by: Smith

Approved by : [Signature]

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**Shenzhen GSI Electronic Technology Co · Ltd**

Address: Room 616 , XianKeJiDian Building , BaGuaSi Road, Shenzhen , China  
Tel:(86)755-25844177 Fax:(86)755-25844877 Http://www.szjisihai.com



Test Results:

No.	Component	Material	Issue Body	Report No & Issue Date	Test Data (PPM)
1		PCB	SGS	SH9075112/CHEM Date: Oct. 05, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
2		Chip capacitor	SGS	TJTC 1003985/CHEM Date: Mar. 19, 2010	Cd: N.D. Pd: 19.3 Hg: N.D. Cr6: N.D.
3		Chip resistors	SGS	SZ90400858-2.1 Date: APR. 25, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
4		Chip diode	SGS	TJTC 0906985/CHEM Date: Jun 2, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
5		Chip transistor	SGS	GZMR090903476 Date: Sep. 11, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
6	IC	The body of IC U2	SGS	SH9005125/CHEM Date: MAY 09, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: 514.9
		The pin of IC U2			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
7	IC	The body of IC U5	SGS	TJTC 0904749CHEM Date: Apr.17, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D.
		The pin of IC U5			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
8		transistor Q7	SGS	TJTC 0906985/CHEM Date: Jun 3, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.

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No.	Component	Material	Issue Body	Report No & Issue Date	Test Data (PPM)
9		transistor Q9	SGS	CE/2009/46081 Date: 2009/10/11	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: Negative
10	Inductor L4	Inductor magnet frame	SGS	CANEC0900076872 Date: 13 May, 2009	Cd: N.D. Pd: 22 Hg: N.D. Cr6: N.D.
		Inductor enameled wire			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
11	crystal	Black plastic	SGS	SH1001466/CHEM Date: Jan. 14, 2010	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		The body of crystal			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		The pin of crystal			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
12		Chip resistors FU1	SGS	SH9134185/CHEM Date: NOV. 18, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
13	Socket	Black plastic	SGS	CANEC0912002878 Date: 02 Dec, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Metal holder			Cd: N.D. Pd: 83 Hg: N.D. Cr6: Negative

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No.	Component	Material	Issue Body	Report No & Issue Date	Test Data (PPM)
14	Electrolytic capacitor	Black plastic	SGS	SH9022720/CHEM Date: Sep. 22, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Rubber			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Electrolytic liquid			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Electrolytic paper			Cd: N.D. Pd: 8mg/kg Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Aluminum shell			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: Negative
15		Metal sheet	SGS	SH9085403/CHEM Date: AUG 26, 2009	Cd: N.D. Pd: 16.5 Hg: N.D. Cr6: Negative
16		Screw	SGS	GZ0910129433/ CHEM Date: OCT. 19, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: Negative
17	Connection block	Black plastic	SGS	GZMR091219969 Date: Dec 04, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D.
		Insert needle			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.

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No.	Component	Material	Issue Body	Report No & Issue Date	Test Data (PPM)
18		Chip transistor	SGS	CANEC091155061 Date: 06 Nov, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
19	PLUG	Metal holder	SGS	ZSR0904170432C Date: 2009. 4. 24	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: Negative
		Brown plastic			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D. PBBS: N.D. PBDES: N.D.
		Insert needle			Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.
20		Metal cover	SGS	TJTC 0901965/CHEM Date: Jan.20, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: Negative
21		Soldering tin	SGS	SH9000295/CHEM Date: Sep. 23, 2009	Cd: N.D. Pd: N.D. Hg: N.D. Cr6: N.D.

**Note:**

- N.D.=not detected
- ppm=mg/kg
- Photograph is included

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Photograph of Sample



Prof Revolution S2 8000 PCI-E

\*\*\*End of Report\*\*\*

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